

## Description

The VSM58N06 uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in a wide variety of applications.

## General Features

- $V_{DS} = 60V, I_D = 58A$   
 $R_{DS(ON)} < 16m\Omega @ V_{GS} = 10V$  (Typ:  $13m\Omega$ )
- High density cell design for ultra low  $R_{dson}$
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high  $E_{AS}$
- Excellent package for good heat dissipation
- Special process technology for high ESD capability

## Application

- Power switching application
- LED backlighting
- Uninterruptible power supply



TO-252



Schematic Diagram

## Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
VSM58N06-T2	VSM58N06	TO-252	-	-	-

## Absolute Maximum Ratings ( $T_C = 25^\circ C$ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	$V_{DS}$	60	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Drain Current-Continuous	$I_D$	58	A
Drain Current-Continuous( $T_C = 100^\circ C$ )	$I_D(100^\circ C)$	41	A
Pulsed Drain Current	$I_{DM}$	120	A
Maximum Power Dissipation	$P_D$	85	W
Debating factor		0.57	$W/^\circ C$
Single pulse avalanche energy <sup>(Note 5)</sup>	$E_{AS}$	290	mJ
Operating Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 To 175	$^\circ C$

## Thermal Characteristic

Thermal Resistance, Junction-to-Case <sup>(Note 2)</sup>	$R_{\theta JC}$	1.76	$^{\circ}\text{C/W}$
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## Electrical Characteristics ( $T_C=25^{\circ}\text{C}$ unless otherwise noted)

Parameter	Symbol	Condition	Min	Typ	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V I <sub>D</sub> =250μA	60	-	-	V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =60V,V <sub>GS</sub> =0V	-	-	1	μA
Gate-Body Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V,V <sub>DS</sub> =0V	-	-	±100	nA
On Characteristics <sup>(Note 3)</sup>						
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> ,I <sub>D</sub> =250μA	2	3	4	V
Drain-Source On-State Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =30A	-	13	16	mΩ
Forward Transconductance	g <sub>FS</sub>	V <sub>DS</sub> =5V,I <sub>D</sub> =30A	30	-	-	S
Dynamic Characteristics <sup>(Note4)</sup>						
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> =25V,V <sub>GS</sub> =0V, F=1.0MHz	-	2498	-	PF
Output Capacitance	C <sub>oss</sub>		-	185	-	PF
Reverse Transfer Capacitance	C <sub>rss</sub>		-	80	-	PF
Switching Characteristics <sup>(Note 4)</sup>						
Turn-on Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> =30V,I <sub>D</sub> =2A,R <sub>L</sub> =1Ω V <sub>GS</sub> =10V,R <sub>GEN</sub> =3Ω	-	12	-	nS
Turn-on Rise Time	t <sub>r</sub>		-	5.2	-	nS
Turn-Off Delay Time	t <sub>d(off)</sub>		-	38	-	nS
Turn-Off Fall Time	t <sub>f</sub>		-	27	-	nS
Total Gate Charge	Q <sub>g</sub>	V <sub>DS</sub> =30V,I <sub>D</sub> =30A, V <sub>GS</sub> =10V	-	36	-	nC
Gate-Source Charge	Q <sub>gs</sub>		-	9.9	-	nC
Gate-Drain Charge	Q <sub>gd</sub>		-	6.6	-	nC
Drain-Source Diode Characteristics						
Diode Forward Voltage <sup>(Note 3)</sup>	V <sub>SD</sub>	V <sub>GS</sub> =0V,I <sub>S</sub> =30A	-	-	1.2	V
Diode Forward Current <sup>(Note 2)</sup>	I <sub>S</sub>		-	-	58	A
Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25°C, I <sub>F</sub> =30A di/dt = 100A/μs <sup>(Note3)</sup>	-	35		nS
Reverse Recovery Charge	Q <sub>rr</sub>		-	47		nC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

## Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Surface Mounted on FR4 Board,  $t \leq 10$  sec.
3. Pulse Test: Pulse Width  $\leq 300\mu s$ , Duty Cycle  $\leq 2\%$ .
4. Guaranteed by design, not subject to production
5.  $E_{AS}$  condition:  $T_J=25^{\circ}\text{C}, V_{DD}=30V, V_G=10V, L=0.5mH, R_g=25\Omega$

## Test circuit

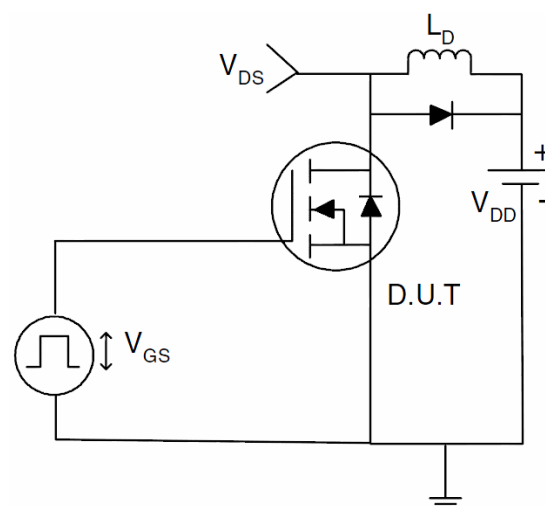
### 1) $E_{AS}$ test Circuits

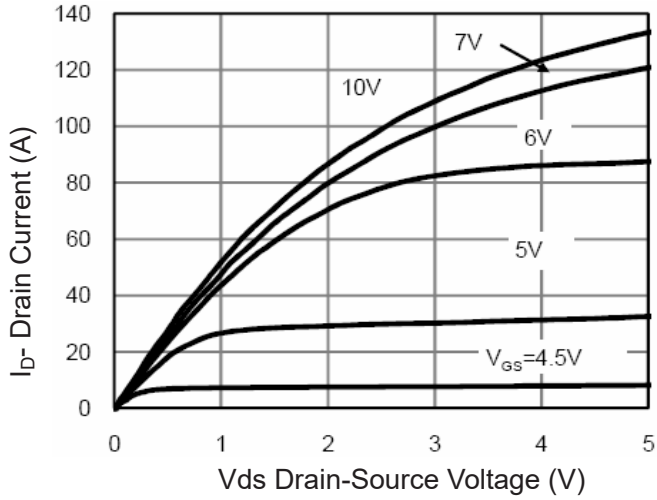
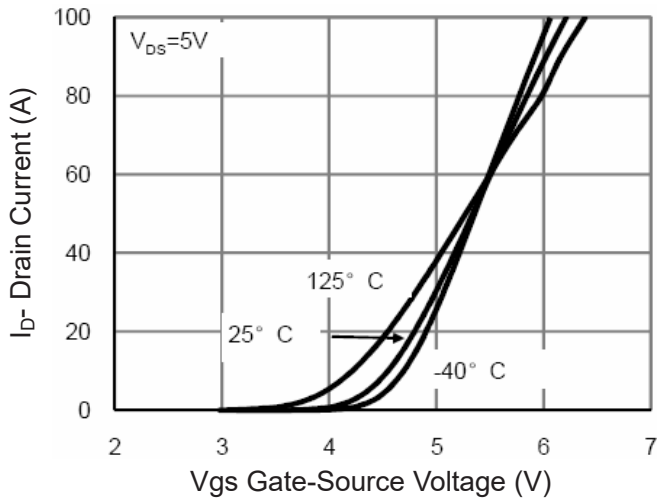
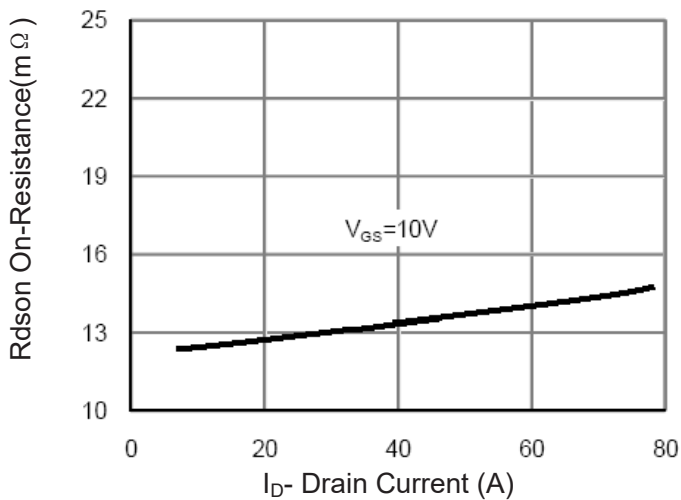
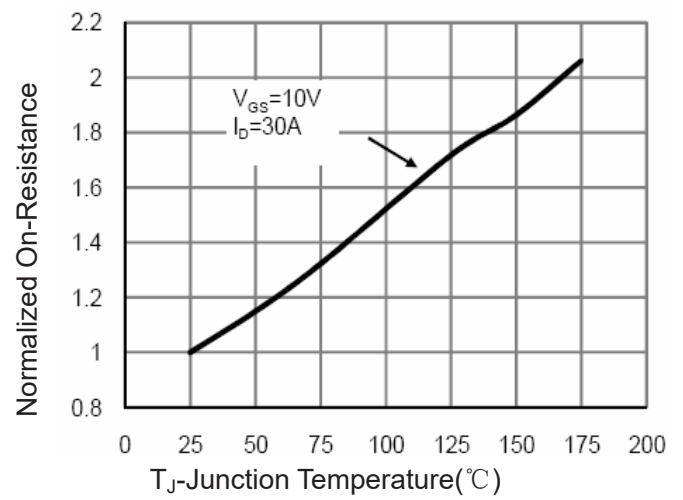
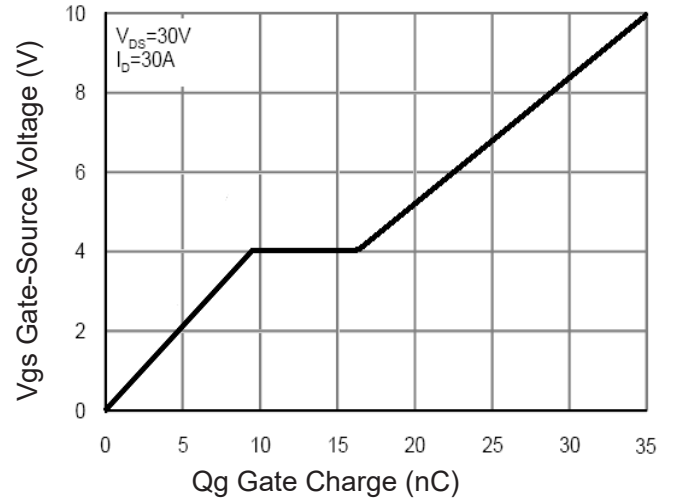
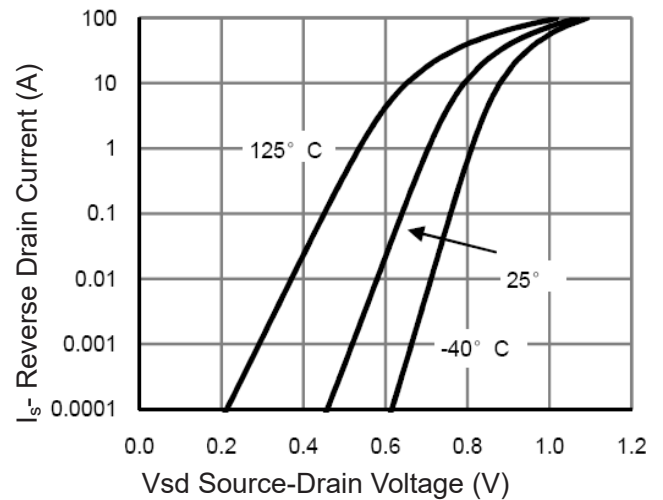


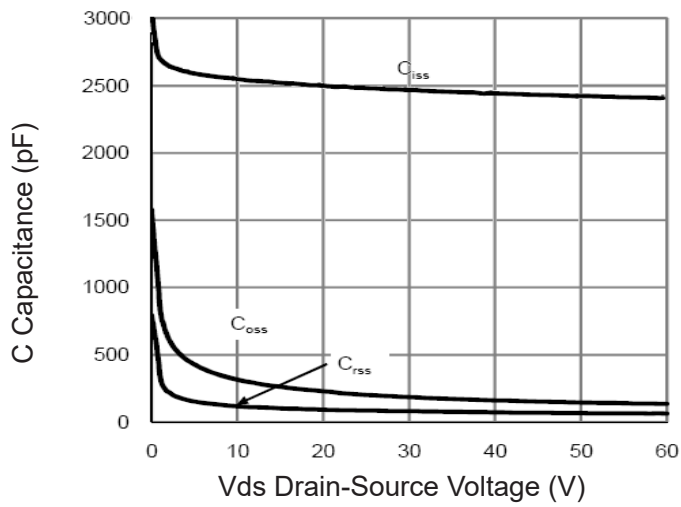
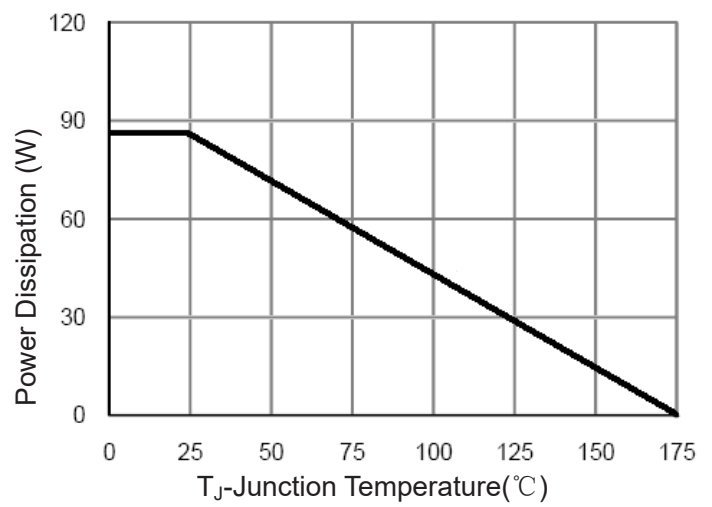
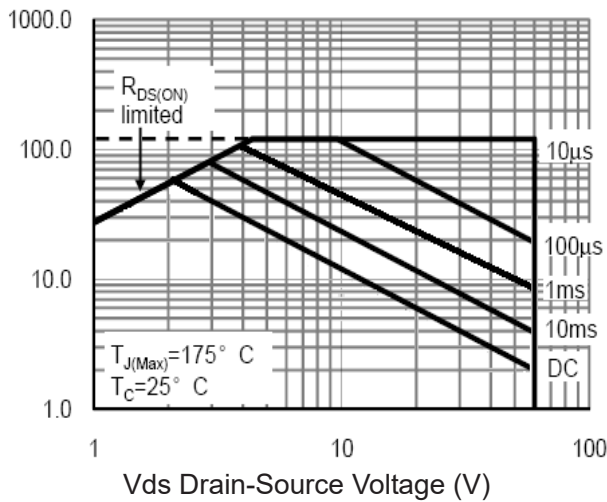
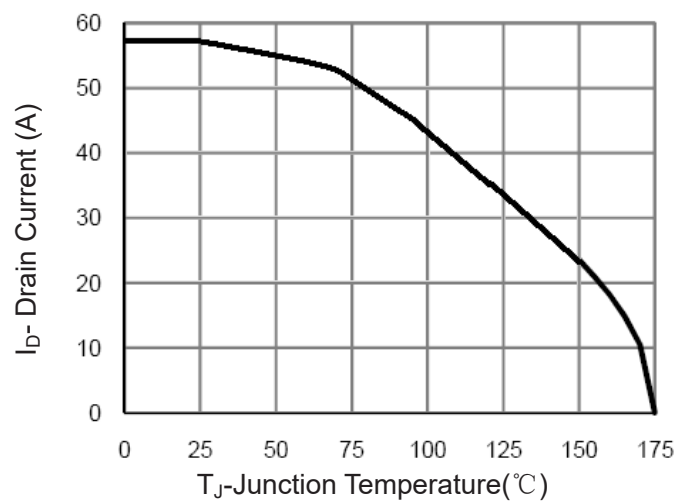
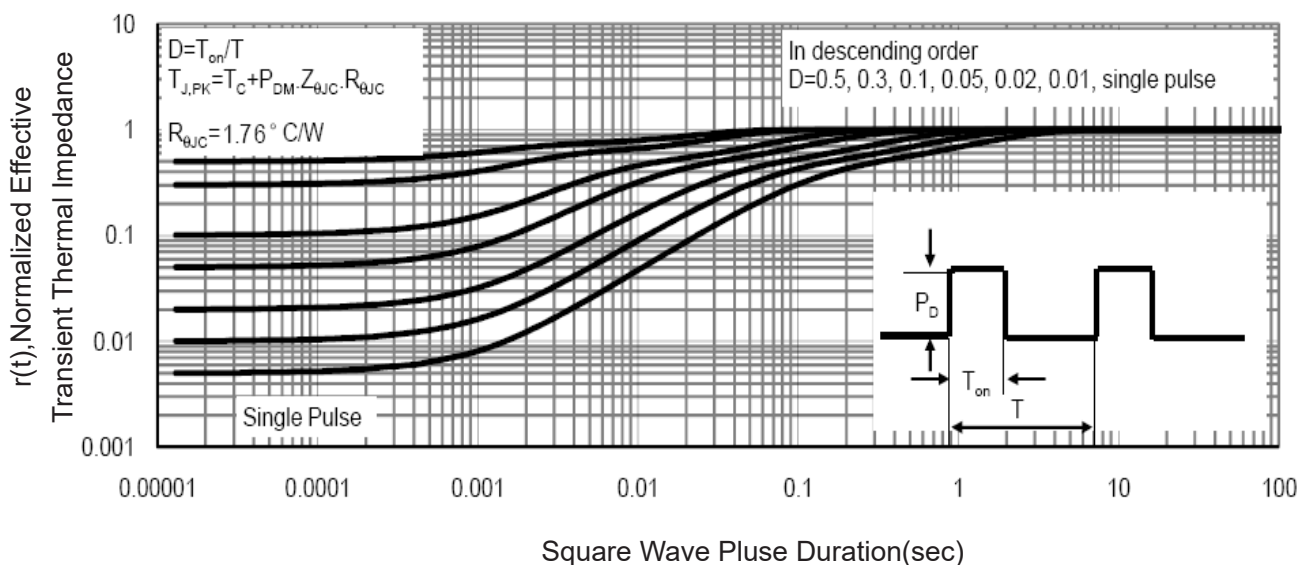
### 2) Gate charge test Circuit



### 3) Switch Time Test Circuit



**Typical Electrical and Thermal Characteristics (Curves)**

**Figure 1 Output Characteristics**

**Figure 2 Transfer Characteristics**

**Figure 3 Rdson- Drain Current**

**Figure 4 Rdson-Junction Temperature**

**Figure 5 Gate Charge**

**Figure 6 Source- Drain Diode Forward**


**Figure 7 Capacitance vs Vds**

**Figure 9 Power De-rating**

**Figure 8 Safe Operation Area**

**Figure 10  $I_D$  Current- Junction Temperature**

**Figure 11 Normalized Maximum Transient Thermal Impedance**